

EXHIBIT B

Bounding uncertainty in the static timing analysis of digital PD-SOI

Circuits

(with application to static noise analysis)

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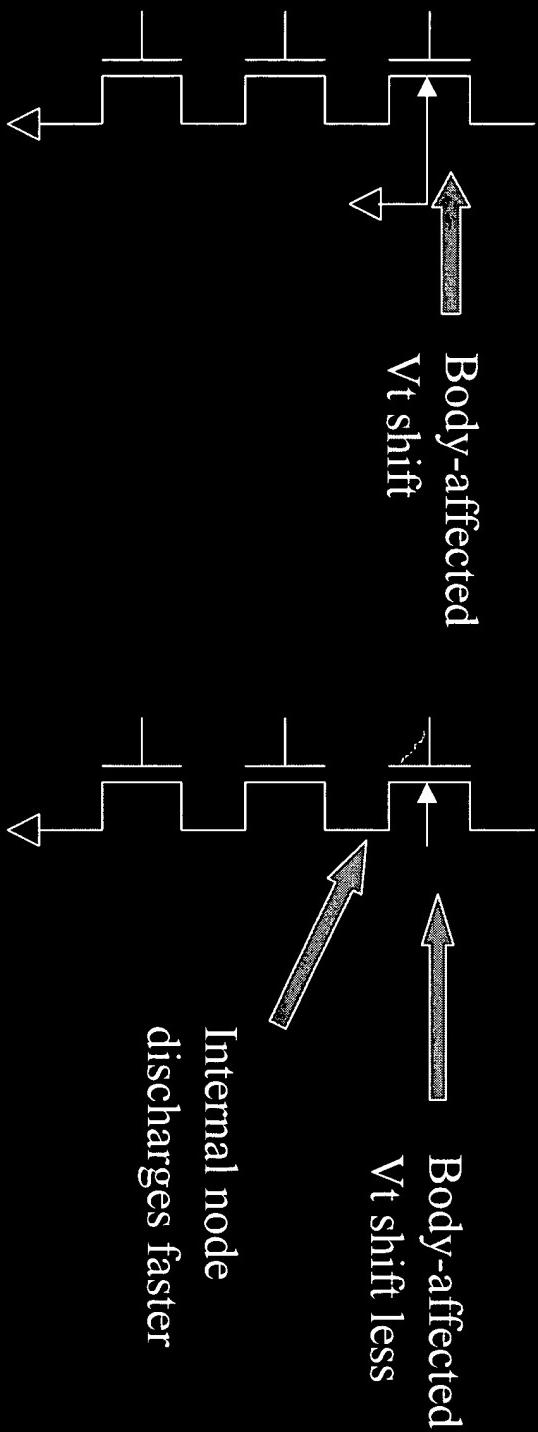
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Advantages of SOI

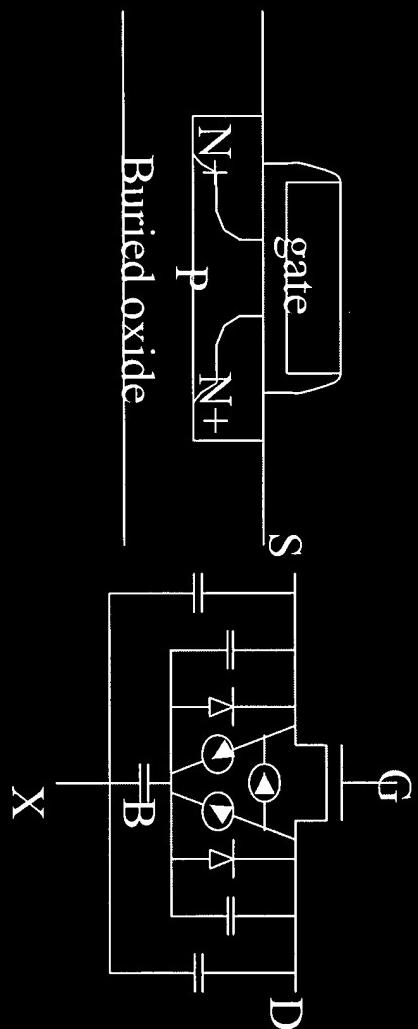
- Reduced source/drain diffusion capacitance
- Improved stack performance
- Some reduction in wire capacitance
- Gives advantage to certain circuit families (e. g. passgates)



Target technology for experiments

- IBM Sematech "benchmark" technology
 - $L_{\text{drawn}} = 0.35 \mu\text{m}$
 - $T_{\text{ox}} = 4.5 \text{ nm}$
 - $T_{\text{box}} = 80 \text{ nm}$
- Core simulation technology is spice3f5 wrapped with an API and BSIM3-SOI models. Still debugging transient analysis accuracy!

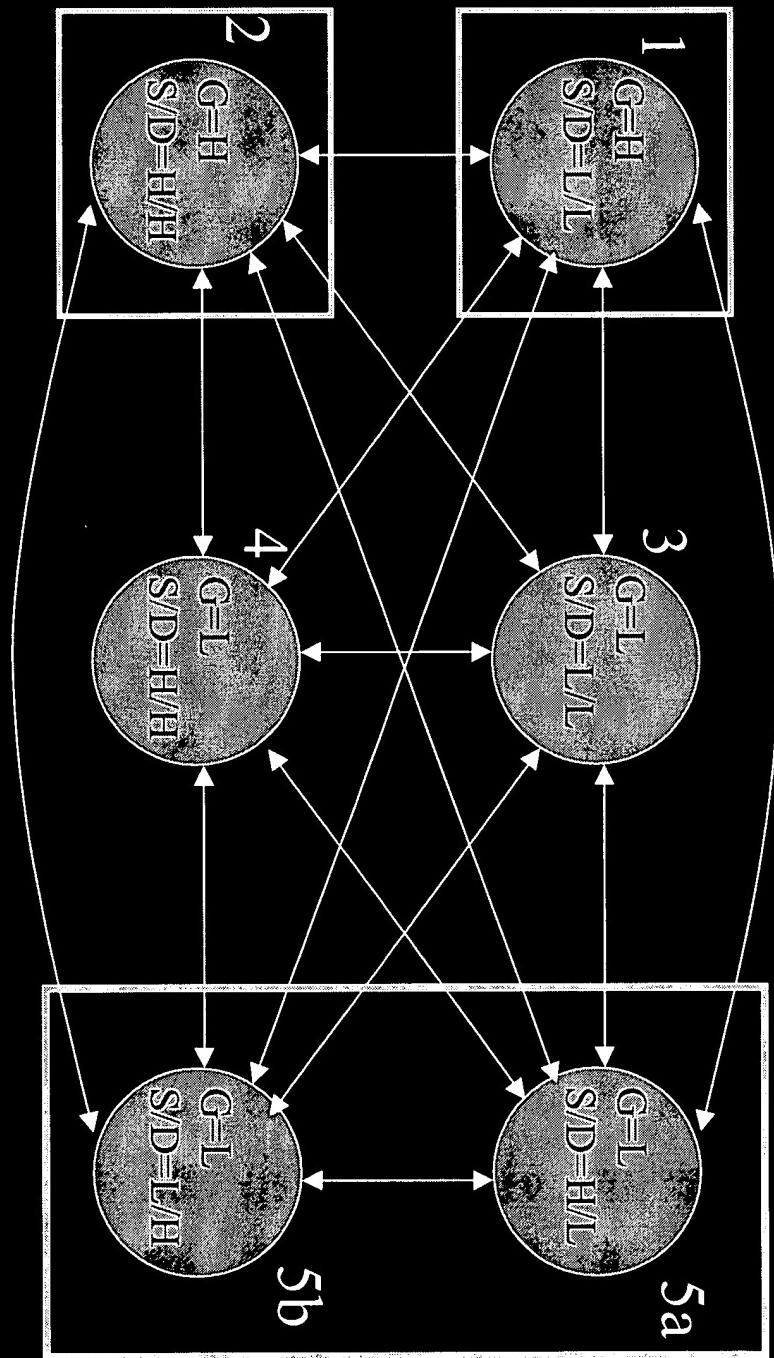
Body voltage determined by...



- Capacitive coupling of gate, substrate, source, and drain
- Forward-bias diode currents at the source-body and drain-body junctions
- Reverse-bias diode currents at the source-body and drain-body junctions

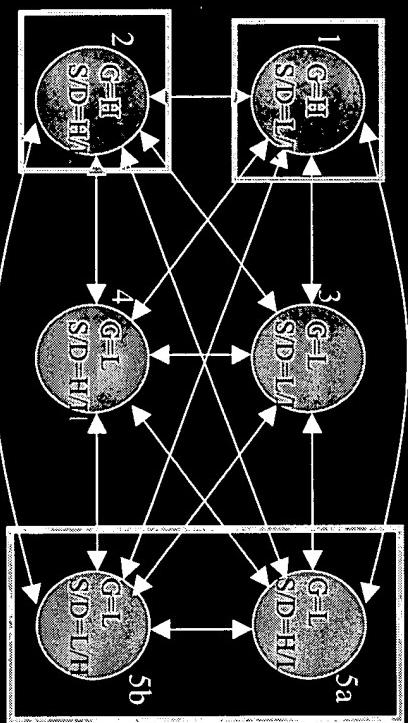
State diagram view of body interactions

nMOS



Device physics in this picture

Each state transition involves a “capacitive” coupling kick:

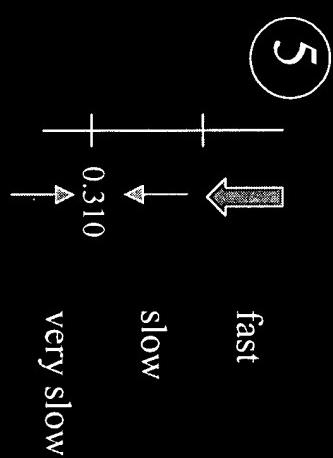
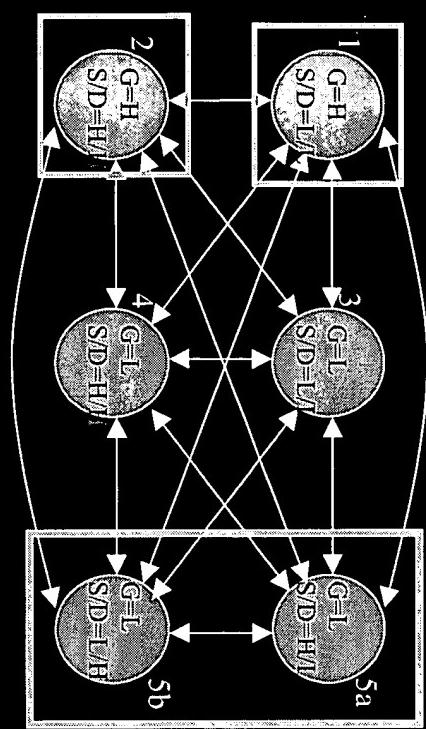


1->2	1200 mV
1->3	-300 mV
1->4	-200 mV
1->5	-200 mV
2->1	-950 mV/-1700 mV
2->3	-1300 mV/-2100 mV
2->4	-1450 mV/-950 mV
2->5	-16 mV/-1800 mV
3->1	300 mV
3->2	1650 mV
3->4	125 mV
3->5	95 mV
4->1	200mV/-1500 mV
4->2	1450 mV/950 mV
4->3	-110 mV/-1500 mV
4->5	-20 mV/-1300 mV
5->1	200 mV
5->2	1500 mV
5->3	-95 mV
5->4	20 mV

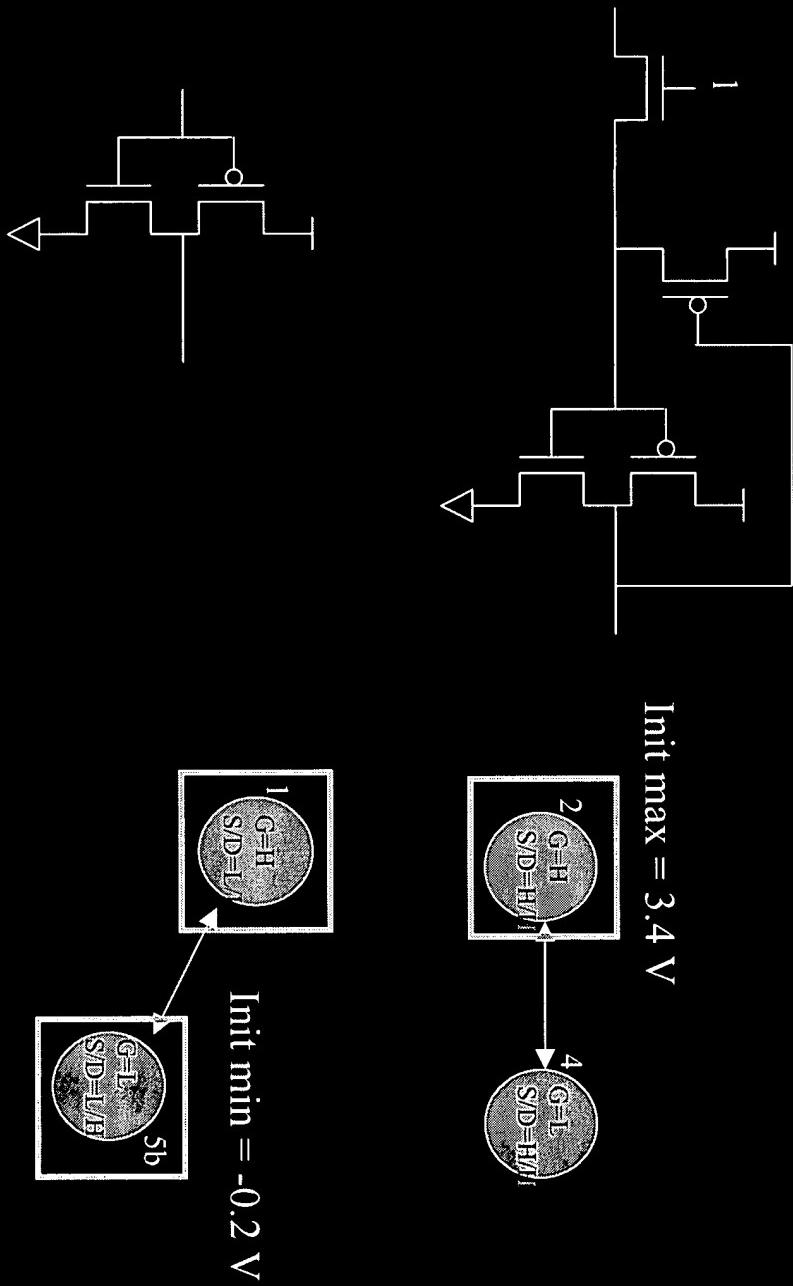
Capacitive kicks largely “reversible” except for cases of forward-bias body discharge. But are important for “initial condition” analysis.

Device physics in this picture

Each state has a steady-state target with relaxation time dependent on deviation from the target.

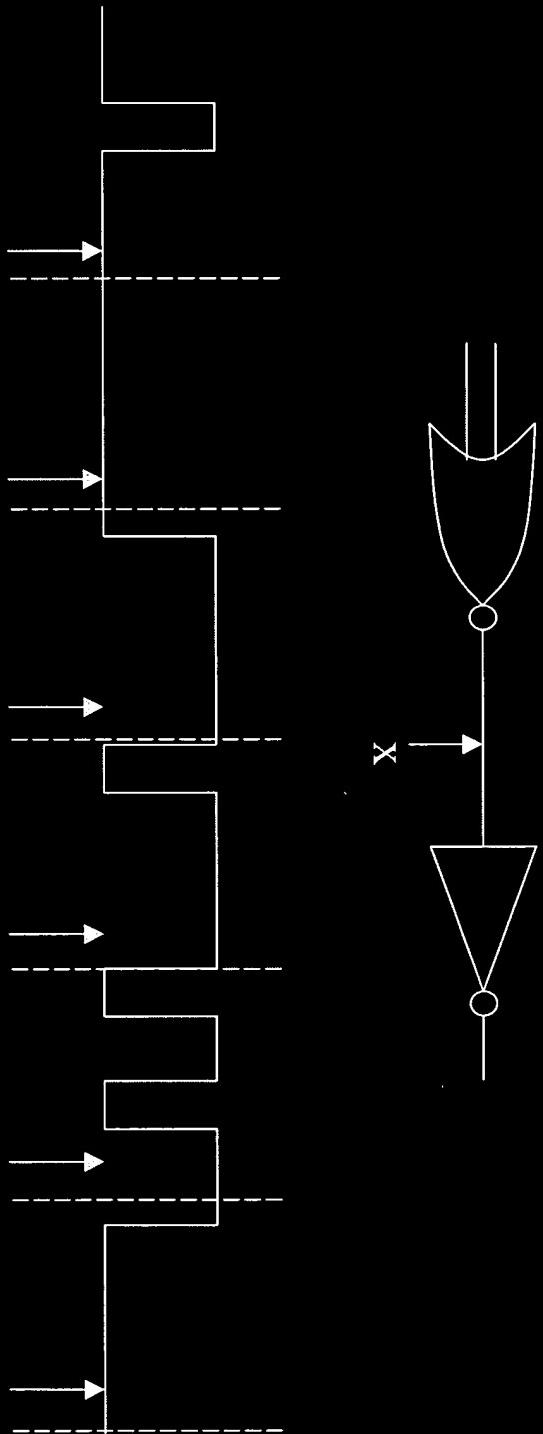


“Initial Condition” analysis



Signal Probability

$P_s(x) =$ Average fraction of clock cycles in which the steady state value of x is a logic high

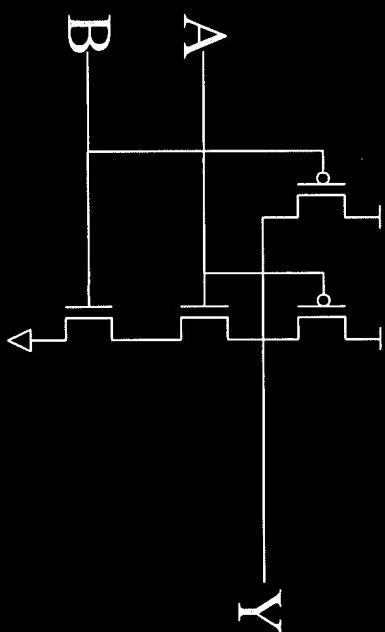


Signal Probability

$$P_s(A) = 0.5$$

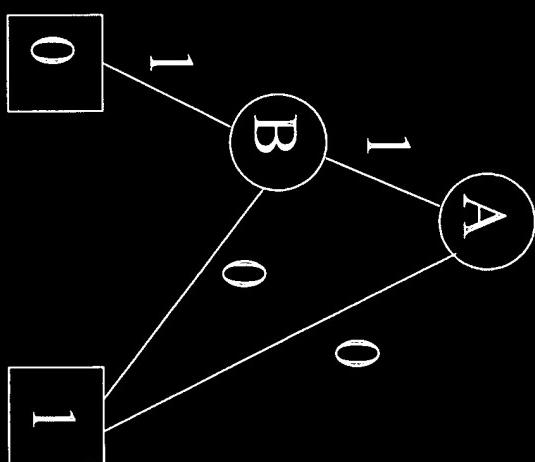
$$P_s(B) = 0.5$$

$$P_s(Y) = 1 - P_s(A)P_s(B) = 0.75$$



Easily done with BDD techniques

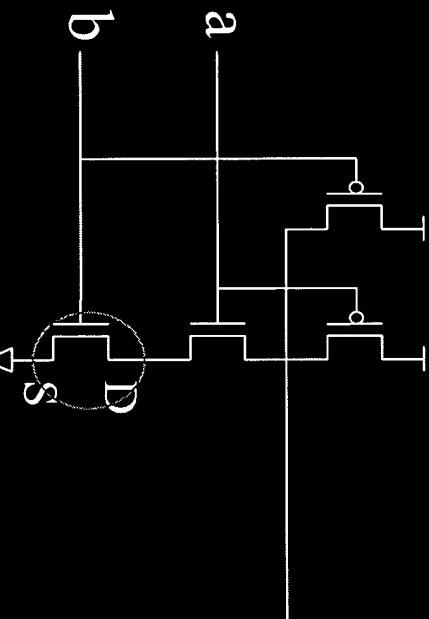
$$P(\wedge A) + P(A)P(\wedge B)$$



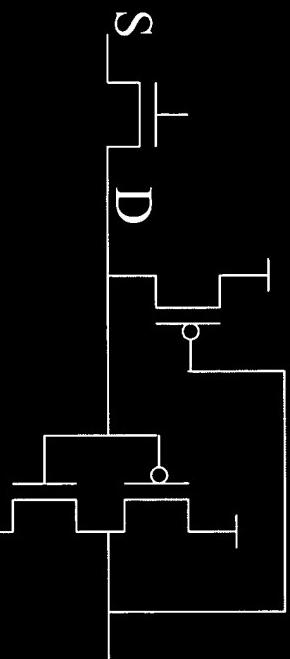
Conditional channel switching probabilities

Do NOT sum to 1

$$\begin{array}{l} P(D|\wedge b) = P(a) \\ P(\wedge D|\wedge b) = 0 \\ P(S|b) = 0 \\ P(\wedge S|\wedge b) = 1 \end{array}$$



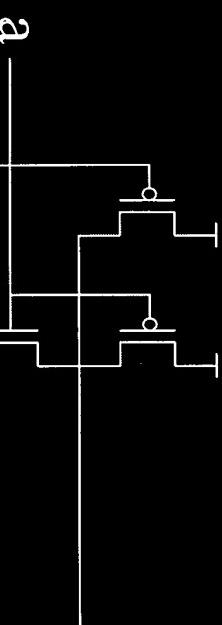
$$\begin{array}{ll} P(S|G) = 0.5 & P(D|\wedge G) = 0 \\ P(\wedge S|G) = 0.5 & P(\wedge D|\wedge G) = 0 \\ P(\wedge S|\wedge G) = 0.5 & \\ P(S|\wedge G) = 0.5 & \end{array}$$



Done through a path search assuming both temporal and spatial independence of CCC input variables.

Hazards

a



b

R max/min = 200/800
F max/min = 200/800

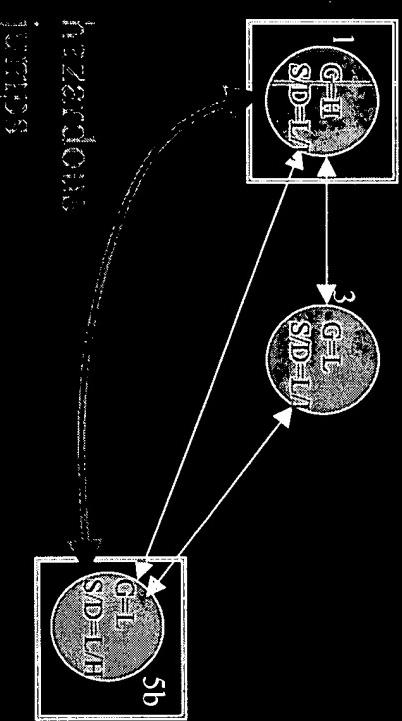
R max/min = 400/600
F max/min = 400/600

b = H

D F max = 600
D F min = 400
D R max = NA
D R min = NA

b = L

D R max = 800
D R min = 200
D F max = NA
D R min = NA



Monte Carlo analysis

Inputs

signal probability of gate

channel conditional probabilities on

gate disposition

channel conditional hazard R/F times

on gate disposition

Process (done separately for min and max)

use first two cycles to establish initial

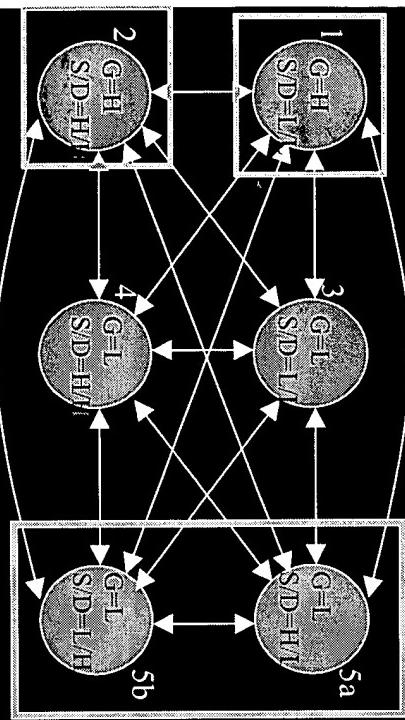
condition

then use probabilities:

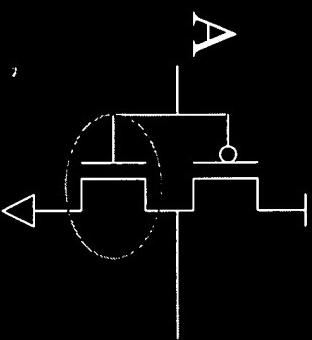
assign next gate using signal probability
given next gate assignment, find S/D

assignment

given current state and next state, affect
transition to achieve min/max
result, allowing hazards



Monte Carlo results

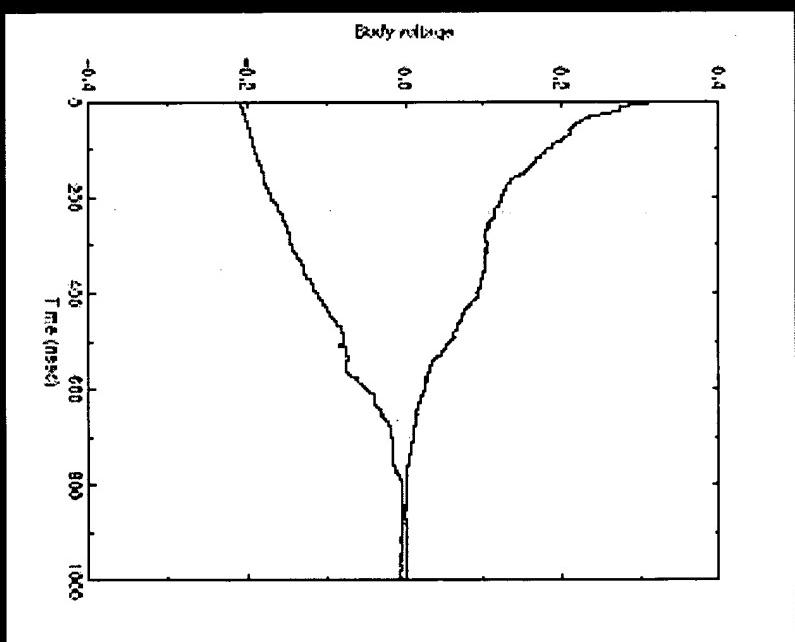
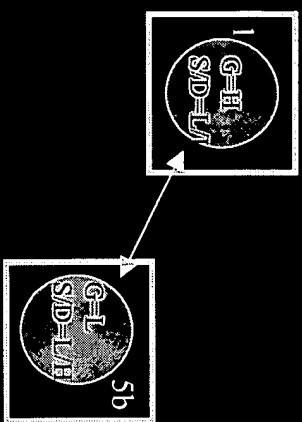


G/S/D = L/L/H

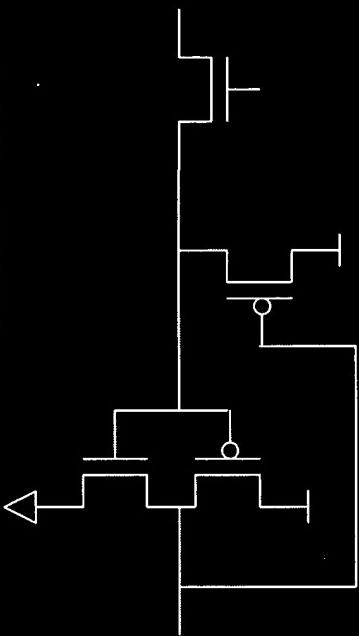
P(A) = 0.5

T_{cycle} = 1000 psec

R/F min/max = 400 ps / 600 ps



Monte Carlo results (con't)

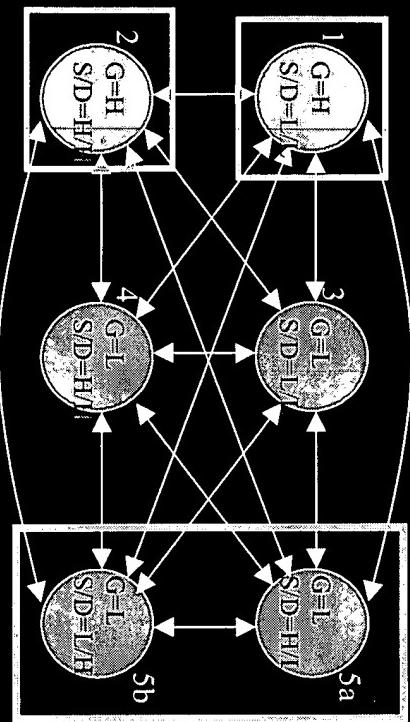
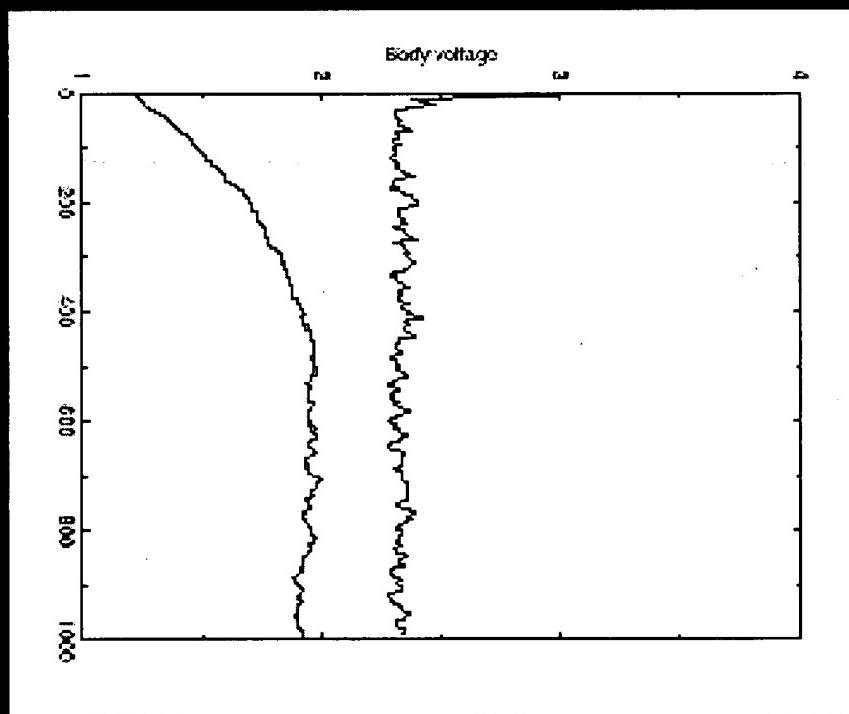


G/S/D = H/H/H

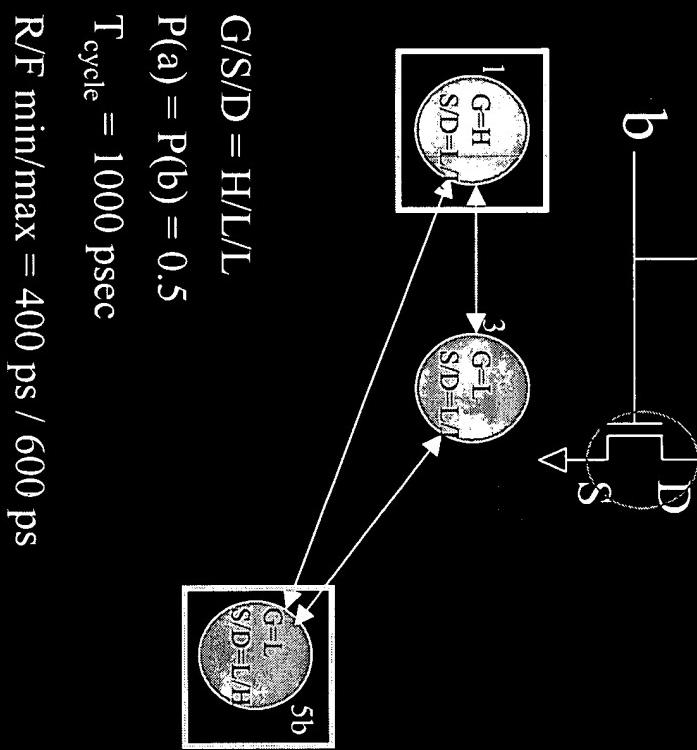
All probabilities are 0.5

T_{cycle} = 1000 psec

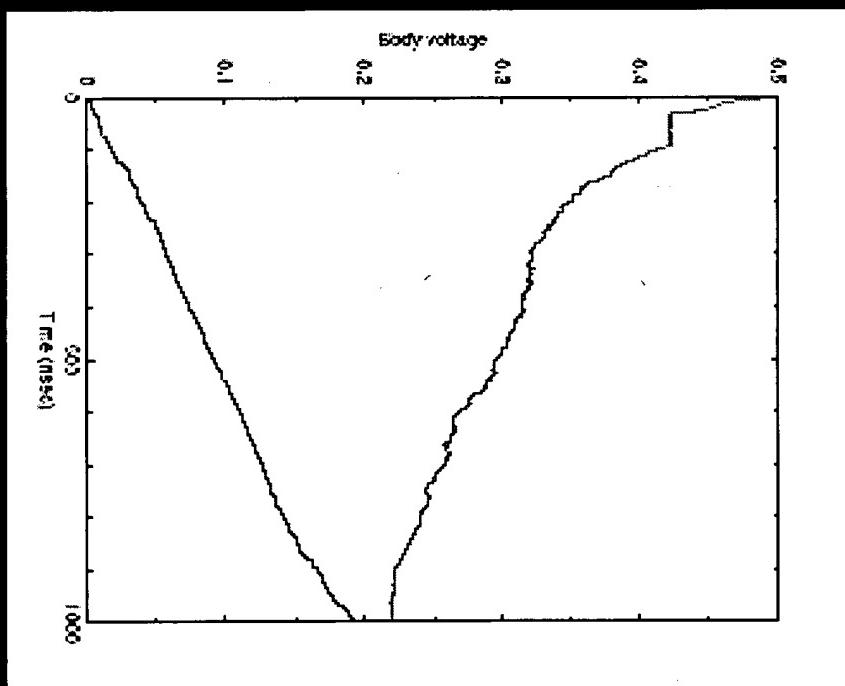
R/F min/max = 400 ps / 600 ps



Monte Carlo results (con't)



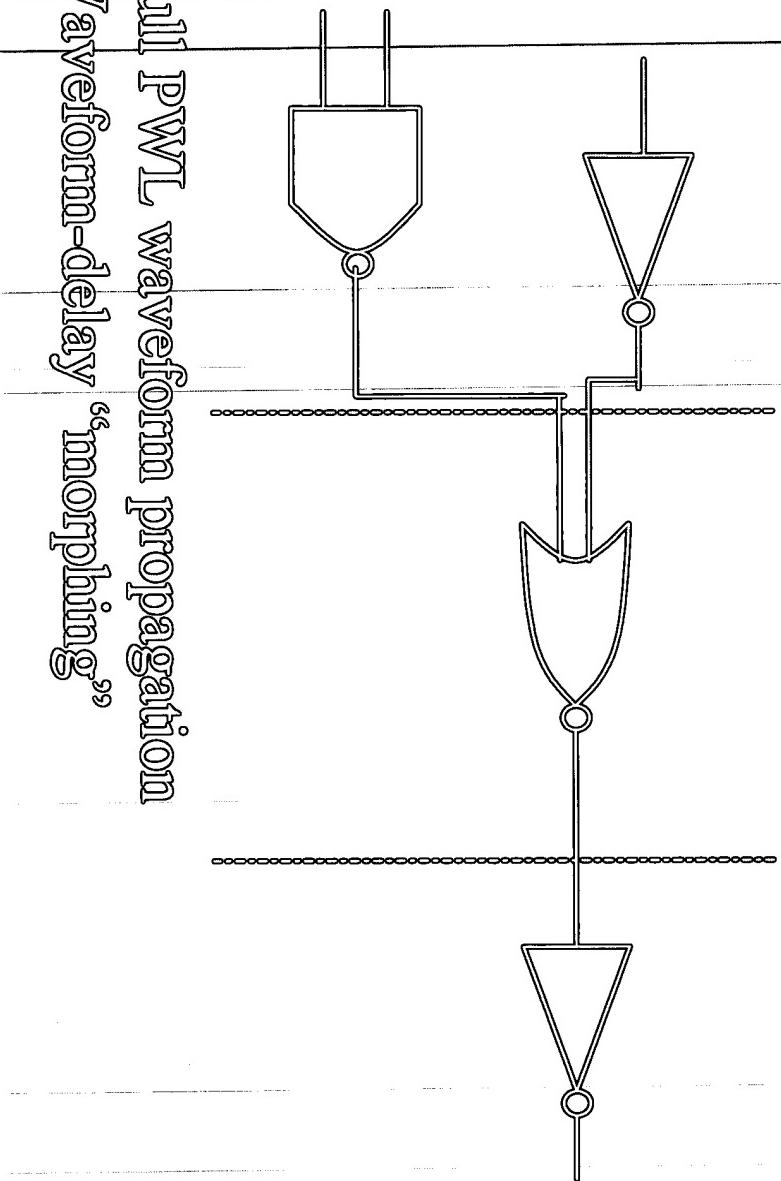
$G/S/D = H/L/L$
 $P(a) = P(b) = 0.5$
 $T_{cycle} = 1000 \text{ psec}$
 $R/F \text{ min/max} = 400 \text{ ps} / 600 \text{ ps}$



Integrated static timing and body

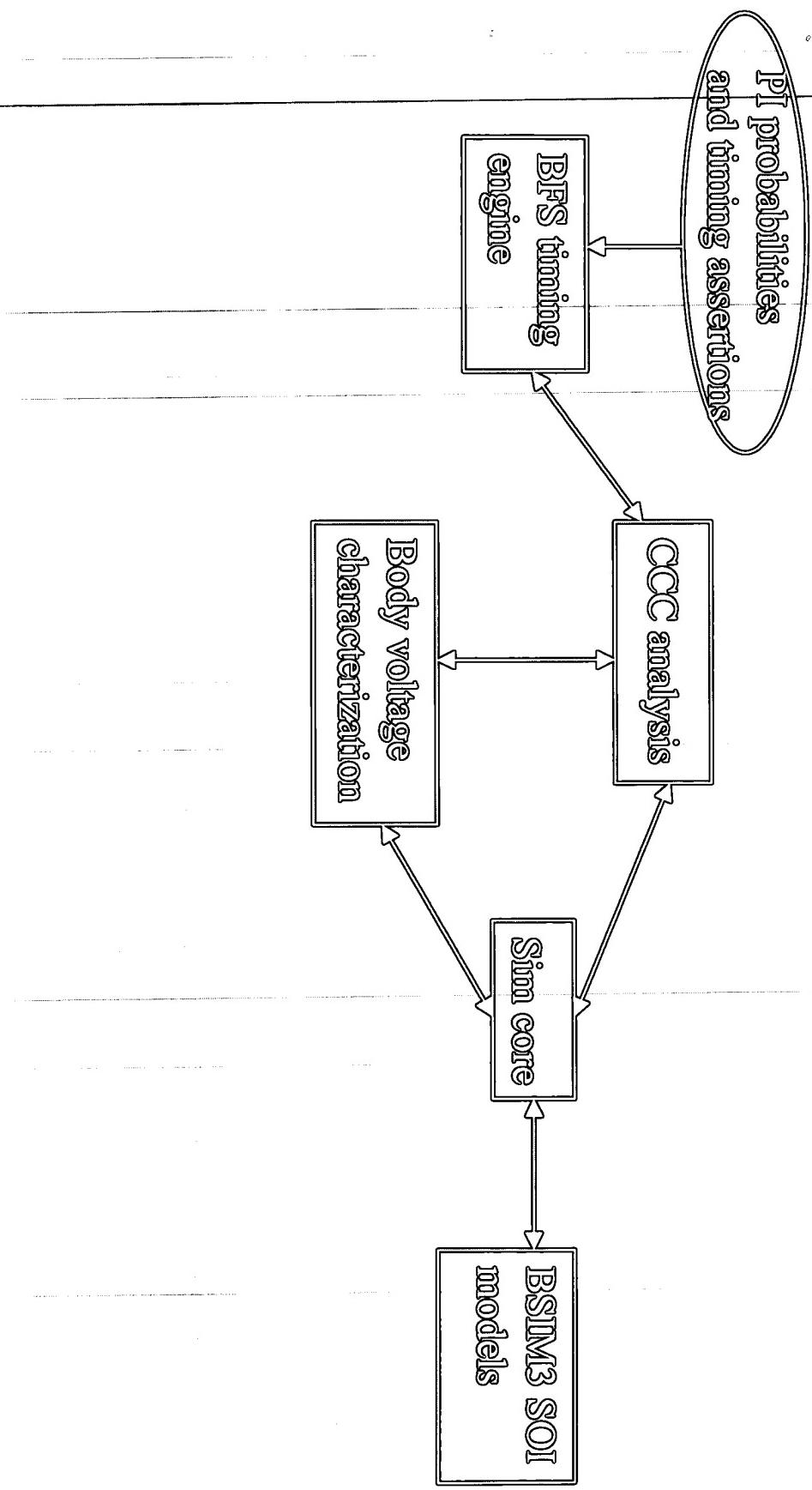
Voltage analysis

BFS transistor-level static timing analysis engine



Full PWL waveform propagation
Waveform-delay “morphing”

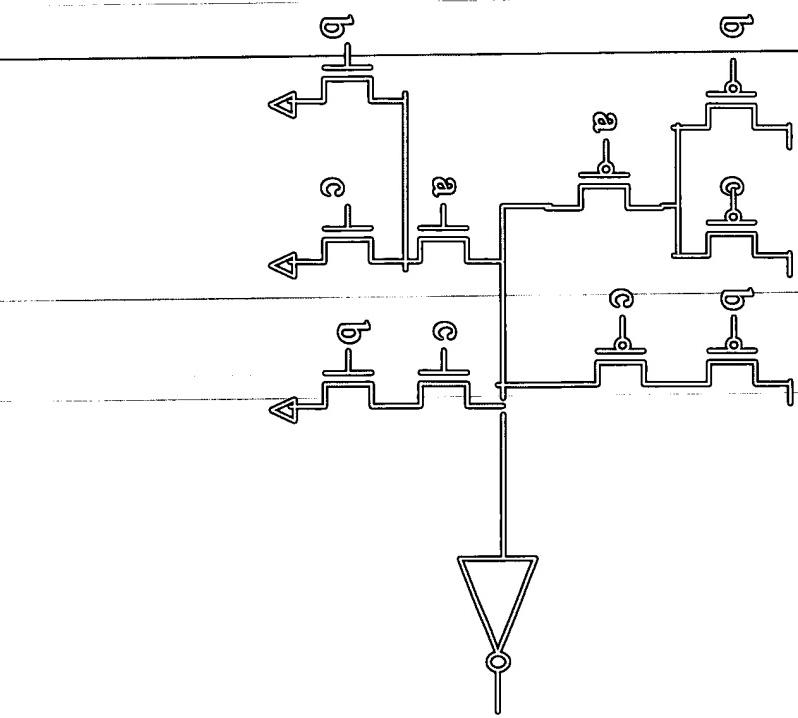
Architecture of prototype



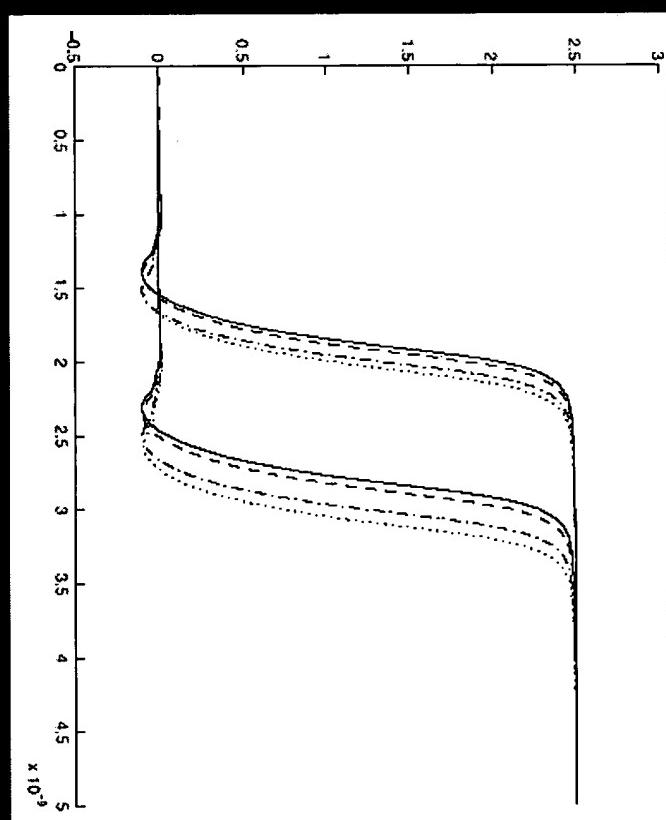
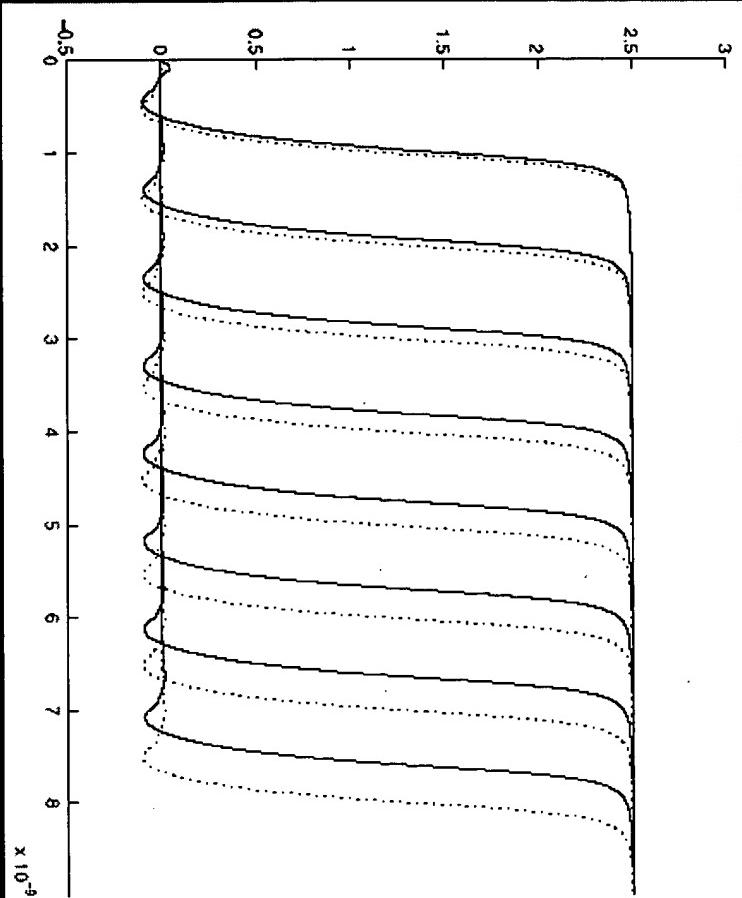
Preliminary timing results

Static ripple-carry adder

16 stages



Preliminary timing results



Stochastic methods for timing and noise?

Timing tool allows you to immediately identify paths subject to huge "initial condition" delay variability or noise sensitivity that can be reigned in with conservative assumptions of switching activity.

- Body voltages can be applied to static noise analysis
- Integrated timing/noise/body voltage solution required!

Observation: Those circuits that have the most advantage in SOI show the greatest "discrepancy" between initial and steady state results.

